

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination DOUMAE, YASUHIRO	
		Examiner	Art Unit	Page 1 of 1
		William C. Vesperman	2813	

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	"A Novel Self-aligned Gate-overlapped LDD Poly-Si TFT with High Reliability and Performance", published in the IEEE in 1977 and authored by Mutsuko Hatano, Hajime Akimoto and Takeshi Sakai.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.